SN54F37, SN74F37
QUADRUPLE 2-INPUT POSITIVE-NAND BUFFERS

D3206, JANUARY 1989—REVISED APRIL 1989

- **Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs**
- **Dependable Texas Instruments Quality and Reliability**

description

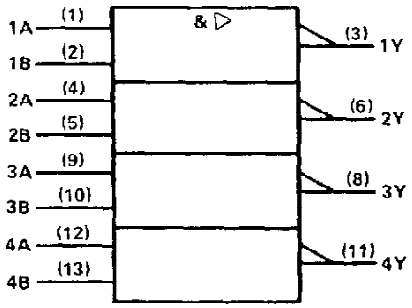
These devices contain four independent 2-input NAND buffer gates. They perform the Boolean functions $Y = \overline{A \cdot B}$ or $Y = \overline{A} + \overline{B}$ in positive logic.

The SN54F37 is characterized for operation over the full military temperature range of −55°C to 125°C. The SN74F37 is characterized for operation from 0°C to 70°C.

FUNCTION TABLE (each gate)

INPUTS		OUTPUT
A	B	Y
H	H	L
L	X	H
X	L	H

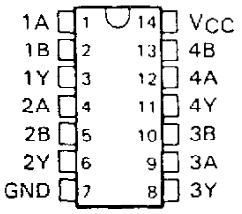
logic symbol†



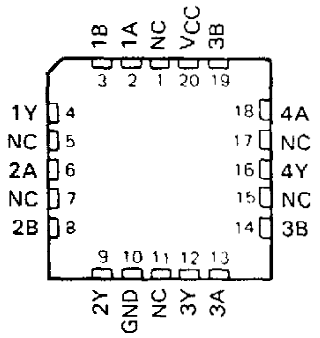
†This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, and N packages.

SN54F37 . . . J PACKAGE
SN74F37 . . . D OR N PACKAGE
(TOP VIEW)

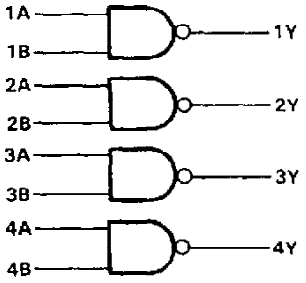


SN54F37 . . . FK PACKAGE
(TOP VIEW)



NC – No internal connection

logic diagram (positive logic)



TEXAS INSTRUMENTS
POST OFFICE BOX 655012 • DALLAS, TEXAS 75265

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} . . . . . −0.5 V to 7 V
Input voltage† . . . . . −0.5 V to 7 V
Input current . . . . . −30 mA to 5 mA
Voltage applied to any output in the high state . . . . . −0.5 V to V_{CC}
Current into any output in the low state . . . . . 128 mA
Operating free-air temperature range: SN54F37 . . . . . −55°C to 125°C
SN74F37 . . . . . 0°C to 70°C
Storage temperature range . . . . . −65°C to 150°C

†The input voltage ratings may be exceeded provided the input current ratings are observed.

recommended operating conditions

		SN54F37			SN74F37			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.8			0.8	V
I_{IK}	Input clamp current			−18			−18	mA
I_{OH}	High-level output current			−15			−15	mA
I_{OL}	Low-level output current			48			64	mA
T_A	Operating free-air temperature	−55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		SN54F37			SN74F37			UNIT
			MIN	TYP†	MAX	MIN	TYP†	MAX	
V_{IK}	V_{CC} = 4.5 V,	I_I = −18 mA		−0.73	−1.2			−1.2	V
V_{OH}	V_{CC} = 4.5 V,	I_{OH} = −1 mA	2.5	3.4		2.5	3.4		V
	V_{CC} = 4.5 V,	I_{OH} = −15 mA	2			2			
	V_{CC} = 4.75 V,	I_{OH} = −1 mA				2.7			
V_{OL}	V_{CC} = 4.5 V	I_{OL} = 48 mA		0.35	0.5				V
		I_{OL} = 64 mA					0.40	0.55	
I_I	V_{CC} = 5.5 V,	V_I = 7 V			0.1			0.1	mA
I_{IH}	V_{CC} = 5.5 V,	V_I = 2.7 V			20			20	μA
I_{IL}	V_{CC} = 5.5 V,	V_I = 0.5 V			−0.6			−0.6	mA
I_{OS}‡	V_{CC} = 5.5 V,	V_O = 0	−100		−225	−100		−225	mA
I_{CCH}	V_{CC} = 5.5 V,	V_I = 0		3	6		3	6	mA
I_{CCL}	V_{CC} = 5.5 V,	V_I = 4.5 V		23	33		23	33	mA

switching characteristics (see Note 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 5 V, C_L = 50 pF, R_L = 500 Ω, T_A = 25°C			V_{CC} = 4.5 V to 5.5 V, C_L = 50 pF, R_L = 500 Ω, T_A = MIN to MAX§			UNIT
			'F37			SN54F37		SN74F37	
			MIN	TYP†	MAX	MIN	MAX	MIN	MAX
t_{PLH}	A or B	Y	1.5	3.1	5.5	1	7	1.5	6.5	ns
t_{PHL}			1	2.1	4.5	1	6	1	5	

† All typical values are at V_{CC} = 5 V, T_A = 25°C.
‡ Not more than one output should be shorted at a time and the duration of the short circuit should not exceed one second.
§ For conditions shown as MIN or MAX, use the appropriate value specified under Recommended Operating Conditions.
NOTE 1: Load circuits and waveforms are shown in Section 1 of the *F Logic Data Book, 1989*.

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